SYSTEM VALVE SUBCODE CODE CAUGI COMM XIO [G] (13) U1(14) OCCUBBLINCE HEVISION EVENT YEAR REPORT NO CODE TYPE NO. 0 0 0 8 10 1 COMPONENT MANUFACTURE ATTACHMENT FORM SUB SUPPLIER 000 0 N (24) IG 10 18 10

[1 [0] Electronic IC failure possibly caused by voltage spike during calibration. The GE

[1] | model 136B1333G1 gain change card was replaced and SI 4.2.C-2 (calibration and

[1] [functional test) was completed. This is considered a random failure and no

1 3 | recurrence control is required.

GAUSE DESCRIPTION AND CORRECTIVE ACTIONS (27)

TAGISTIC SPONER OTHERSTATIC (B) MINIBOTON DESCRIPTION (B)

I S E 28 I O O 25 NA

B (3) Surveillance test

I G Z (1) Z (14) NA

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NOME TO DESCRIPT A SPECIAL SERVICE OF SCHOOL SER

THE POSINE INDICATE TO FACILITY (13)

NA PROBLEM PROBLEM (43)

Gene Holder (205) 729-6134

LER SUPPLEMENTAL INFORMATION

BFRO-50- 260 /82008 Technical Specification Involved Table 3.2.C
Reported Under Technical Specification 6.7.2.b(2) * Date Due NRC 2/26/82
Date of Occurrence 1/27/82 Time of Occurrence 1430 Unit 2
Identification and Description of Occurrence: After calibration, unit 2 rod block monitor channel B failed to pass the
functional test of SI 4.2.C-2.

Conditions Prior to Occurrence; Unit 1 in routine shutdown.

Unit 2 at 100%.

Unit 3 in refueling outage

Action specified in the Technical Specification Surveillance Requirements met due to inoperable equipment. Describe.

Apparent Cause of Occurrence:

Electronic IC failure possibly caused by voltage spike during calibration.

Analysis of Occurrence:

There was no effect on the health or safety of the public, no release of activity, no damage to the plant or equipment, and no resulting significant chain of events.

Corrective Action:

The GE model 136B1333G1 gain change card was replaced and SI 4.2.C-2 (calibration and functional test) was completed. This is considered a random failure and no further recurrence control is required.

Failure Data: None

Retention: Period - Lifetime; Responsibility - Document Control Supervisor

*Revision: ALWamer